

MILITARY SPECIFICATION

MICROCIRCUITS, MONOLITHIC SILICON INTERFACE,  
 DUAL PERIPHERAL DRIVERS

This amendment forms a part of MIL-M-38510/129A, dated 6 December 1985, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 1

- \* 1.2.1, Device type 01 and 06: Delete "Dual NAND gate" and substitute "Dual NAND/AND gate".

PAGE 2

- 1.3, Junction temperature ( $T_J$ ): Delete "+175°C" and substitute "+150°C".

PAGE 8

- \* TABLE I, propagation delay time (low to high level output), device types 03, 05, 07, 08 and 09, delete and substitute the following:

"

Propagation delay time (low to high level output)	$t_{PLH}$	$V_{CC} = 4.5 \text{ V},$ $C_L = 100 \text{ pF},$ $R_L = 50 \Omega,$ $I_O = 200 \text{ mA}$	$T_A = 25^\circ\text{C}$	03	-	35	"
				05	-	45	"
	$t_{PLH}$	$V_{CC} = 4.5 \text{ V},$ $C_L = 100 \text{ pF},$ $R_L = 50 \Omega,$ $I_O = 200 \text{ mA}$	$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$	03	-	55	"
				05	-	75	"
	$t_{PLH}$	$V_{CC} = 4.5 \text{ V},$ $C_L = 100 \text{ pF},$ $R_L = 50 \Omega,$ $I_O = 200 \text{ mA}$	$T_A = 25^\circ\text{C}$	07,09	-	55	"
			$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$	07	-	65	"
	$t_{PLH}$	$V_{CC} = 4.5 \text{ V},$ $C_L = 100 \text{ pF},$ $R_L = 50 \Omega,$ $I_O = 200 \text{ mA}$	$T_A = 25^\circ\text{C}$	08,10	-	65	"
			$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$	08	-	95	"
				10	-	90	"

"

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- \* TABLE I, transition time (high to low level output), device type 08, delete and substitute the following:

"

Transition time (high to low level output)	$t_{THL}$	$V_{CC} = 4.5 \text{ V},$ $C_L = 100 \text{ pF},$ $R_L = 50 \Omega,$ $I_O = 200 \text{ mA}$	$T_A = 25^\circ\text{C}$	07,08, 10	-	20	"
			$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$	07,10 08	-	25 35	" "

"

TABLE II, delete and substitute the following:

" TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (see table III) 1/	
	Class S devices	Class B devices
Interim electrical parameters (method 5004)	1	1
Final electrical test parameters (method 5004)	1,2,3,9	1,2,3,9
Group A test requirements (method 5005)	1,2,3,9,10,11	1,2,3,9
Groups C end-point and group B class S, electrical parameters (method 5005)	1,2,3, and table IV delta limits	1 and table IV delta limits
Additional electrical subgroups for group C periodic inspections	N/A	10,11
Group D end-point electrical parameters (method 5005)	1,2,3	1

1/ Indicates PDA applies to subgroup 1 (see 4.2c)."

\* FIGURE 2; The truth table for device type 01 and 06, add the following:

"

A	G	Y	Y'
0	0	1	0
0	1	1	0
1	0	1	0
1	1	0	1

Y is output at the gate.  
Y' is output at the transistor with the gate connected to the base of the transistor. "

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FIGURE 4: Add "NOTE: The measured value of the resistor shall not exceed  $\pm 5\%$  of its branded value due to use, heat, or age." Add this note to figure 4 on page 14 and figure 5 on page 15.

PAGE 45

TABLE III, test no. 42, symbol column: Delete " $I_{CCL2}$ " and substitute " $I_{CCL3}$ ". Make this same change on page 46, test no. 66.

PAGE 46

TABLE III,  $I_{IL1}$ , test nos. 61 and 62, columns 1A and 1B: Delete "0.8 V" and substitute "0.4 V".

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TABLE III,  $t_{PLH}$ , test no. 73, maximum test limits column: Delete "35" and substitute "45".

TABLE III,  $t_{PHL}$ , test no. 77, maximum test limits column: Delete "" and substitute "35".

\* TABLE III,  $t_{PLH}$ , test no. 85, maximum test limits column: Delete "55" and substitute "75". Make this same change on page 53, test no. 97.

TABLE III,  $t_{PHL}$ , test no. 89, maximum test limits column: Delete "" and substitute "55". Make this same change on page 53, test no. 101.

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\* TABLE III,  $t_{PLH}$ , test no. 85, maximum test limits column: Delete "90" and substitute "95". Make this same change on page 71, test no. 97.

\* TABLE III,  $t_{THL}$ , test no. 95 and 96, maximum test limits column: Delete "25" and substitute "35". Make this same change on page 71, test no. 107 and 108.

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\* TABLE III,  $t_{PLH}$ , test no. 85, maximum test limits column: Delete "65" and substitute "70". Make this same change on page 76, test no. 97.

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4.4.3c, delete in its entirety.

PAGE 84

6.2g, delete and substitute the following:

"g. Requirements for special lead lengths, or lead forming, if applicable. These requirements shall not affect the part number. "

NOTE: The margin of this amendment is marked with an asterisk to indicate where changes (additions, modifications, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous amendment.

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Custodians:

Army - ER  
Navy - EC  
Air Force - 17

Review activities:

Army - AR, MI  
Navy - OS, SH, TD  
Air Force - 11, 19, 85, 99  
DLA - ES

User activities:

Army - SM  
Navy - AS, CG, MC

Civil Agency Coordinating Activity:

NASA - NA

Preparing activity:  
Air Force - 17

Agent:  
DLA - ES

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